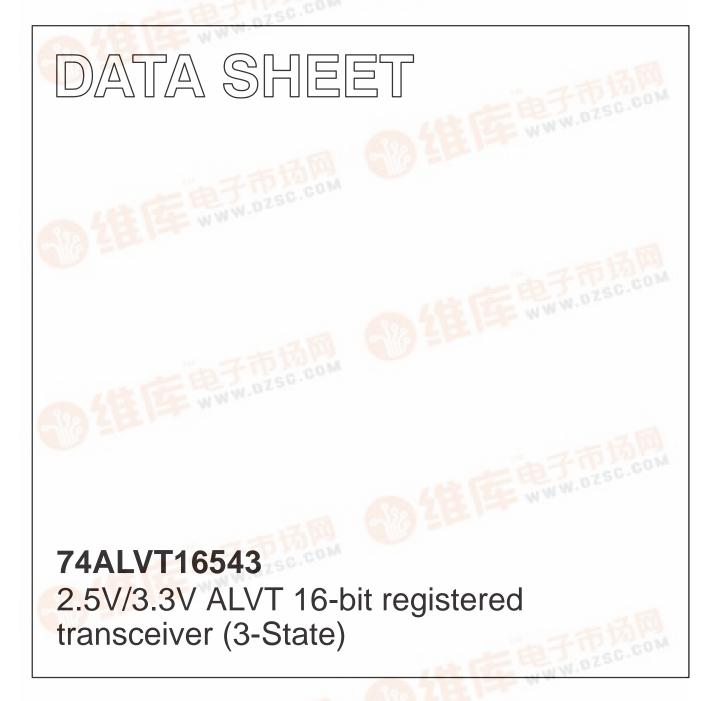
## INTEGRATED CIRCUITS CB打样工厂, 24小时加



Product specification Supersedes data of 1995 Dec 21 IC23 Data Handbook 1998 Feb 13







## 74ALVT16543

#### **FEATURES**

- 16-bit universal bus interface
- 5V I/O Compatible
- 3-State buffers
- Output capability: +64mA/-32mA
- TTL input and output switching levels
- Input and output interface capability to systems at 5V supply
- Bus-hold data inputs eliminate the need for external pull-up resistors to hold unused inputs
- Live insertion/extraction permitted
- Power-up 3-State
- Power-up reset
- No bus current loading when output is tied to 5V bus
- Latch-up protection exceeds 500mA per JEDEC Std 17
- ESD protection exceeds 2000V per MIL STD 883 Method 3015 and 200V per Machine Model

#### DESCRIPTION

The 74ALVT16543 is a high-performance BiCMOS product designed for V<sub>CC</sub> operation at 2.5V or 3.3V with I/O compatibility up to 5V. The device can be used as two 8-bit transceivers or one 16-bit transceiver.

The 74ALVT16543 contains two sets of eight D-type latches, with separate control pins for each set. Using data flow from A to B as an example, when the A-to-B Enable (nEAB) input and the A-to-B Latch Enable (nEAB) input are Low, the A-to-B path is transparent.

A subsequent Low-to-High transition of the nLEAB signal puts the A data into the latches where it is stored and the B outputs no longer change with the A inputs. With nEAB and nOEAB both Low, the 3-State B output buffers are active and display the data present at the outputs of the A latches.

Control of data flow from B to A is similar, but using the nEBA, nLEBA, and nOEBA inputs.

Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

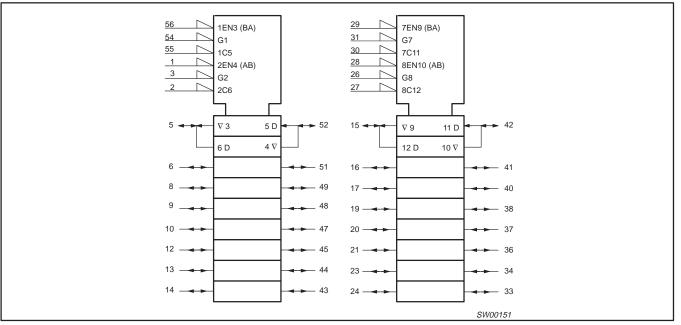
#### QUICK REFERENCE DATA

SYMBOL	PARAMETER	CONDITIONS	TYPI	CAL	UNIT
STWBOL	FARAMETER	T <sub>amb</sub> = 25°C; GND = 0V	2.5V	3.3V	UNIT
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nAx to nBx or nBx to nAx	$C_L = 50 pF$	1.8 2.7	1.6 1.8	ns
C <sub>IN</sub>	Input capacitance DIR, OE	$V_{I} = 0V \text{ or } V_{CC}$	3	3	pF
C <sub>I/O</sub>	I/O pin capacitance	Outputs disabled; $V_{I/O} = 0V$ or $V_{CC}$	9	9	pF
I <sub>CCZ</sub>	Total supply current	Outputs disabled	40	70	μΑ

#### **ORDERING INFORMATION**

PACKAGES	TEMPERATURE RANGE	OUTSIDE NORTH AMERICA	NORTH AMERICA	DWG NUMBER
56-Pin Plastic SSOP Type III	–40°C to +85°C	74ALVT16543 DL	AV16543 DL	SOT371-1
56-Pin Plastic TSSOP Type II	–40°C to +85°C	74ALVT16543 DGG	AV16543 DGG	SOT364-1

#### LOGIC SYMBOL (IEEE/IEC)

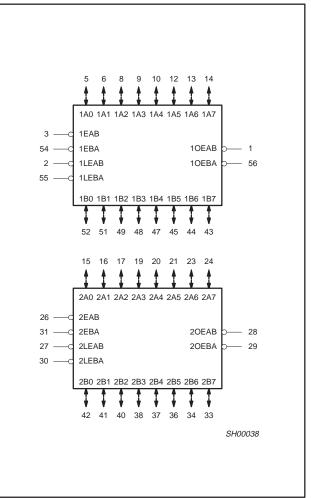


## 74ALVT16543

#### **PIN CONFIGURATION**

1 OEAB 1	56	1 OEBA
1LEAB 2	55	1LEBA
1EAB 3	54	1EBA
GND 4	53	GND
1A0 5	52	1B0
1A1 6	51	1B1
V <sub>CC</sub> 7	50	VCC
1A2 8	49	1B2
1A3 9	48	1B3
1A4 <b>10</b>	47	1B4
GND 11	46	GND
1A5 <b>12</b>	45	1B5
1A6 <b>13</b>	44	1B6
1A7 <b>14</b>	43	1B7
2A0 15	42	2B0
2A1 <b>16</b>	41	2B1
2A2 17	40	2B2
GND 18	39	GND
2A3 19	38	2B3
2A4 20	37	2B4
2A5 21	36	2B5
V <sub>CC</sub> 22	35	VCC
2A6 23	34	2B6
2A7 <b>24</b>	33	2B7
GND 25	32	GND
2EAB 26	31	2EBA
2LEAB 27	30	2LEBA
20EAB 28	29	20EBA
	SH00037	

#### LOGIC SYMBOL

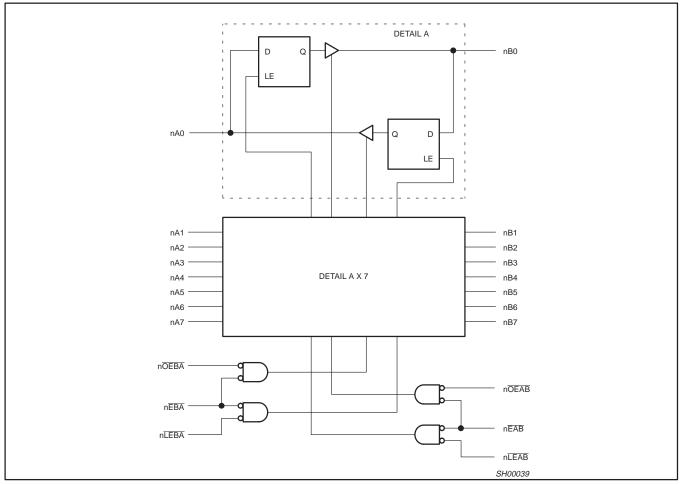


#### **PIN DESCRIPTION**

PIN NUMBER	SYMBOL	NAME AND FUNCTION
5, 6, 8, 9, 10, 12, 13, 14 15, 16, 17, 19, 20, 21, 23, 24	1A0 – 1A7, 2A0 – 2A7	A Data inputs/outputs
52, 51, 49, 48, 47, 45, 44, 43 42, 41, 40,38, 37, 36, 34, 33	1B0 – 1B7, 2B0 – 2B7	B Data inputs/outputs
1, 56 28, 29	10EAB, 10EBA, 20EAB, 20EBA	A to B / B to A Output Enable inputs (active-Low)
3, 54 26, 31	1EAB, 1EBA, 2EAB, 2EBA	A to B / B to A Enable inputs (active-Low)
2, 55 27, 30	1LEAB, 1LEBA, 2LEAB, 2LEBA	A to B / B to A Latch Enable inputs (active-Low)
4, 11, 18, 25, 32, 39, 46, 53	GND	Ground (0V)
7, 22, 35, 50	V <sub>CC</sub>	Positive supply voltage

## 74ALVT16543

#### LOGIC DIAGRAM



#### **FUNCTION TABLE**

	INP	JTS		OUTPUTS	STATUS
nOEXX	nEXX	nLEXX	nAx or nBx	nBx or nAx	514105
Н	Х	Х	Х	Z	Disabled
Х	Н	Х	Х	Z	Disabled
L	$\uparrow \uparrow$	L	h I	Z Z	Disabled + Latch
L	L L	$\stackrel{}{\leftarrow}$	h I	H L	Latch + Display
L	L L	L	H L	H L	Transparent
L	L	Н	Х	NC	Hold

H = High voltage level

= High voltage level one set-up time prior to the Low-to-High transition of nLEXX or nEXX (XX = AB or BA) h

Low voltage level L =

Low voltage level one set-up time prior to the Low-to-High transition of nLEXX or nEXX (XX = AB or BA) =

X = Don't care ↑ = Low-to-Hig  $\hat{\uparrow} = \text{Low-to-High transition of n} \overline{\text{LEXX}} \text{ or n} \overline{\text{EXX}} (XX = AB \text{ or BA})$ NC= No change

Z = High impedance or "off" state

## 74ALVT16543

#### ABSOLUTE MAXIMUM RATINGS<sup>1, 2</sup>

SYMBOL	PARAMETER	CONDITIONS	RATING	UNIT
V <sub>CC</sub>	DC supply voltage		-0.5 to +4.6	V
I <sub>IK</sub>	DC input diode current	V <sub>1</sub> < 0	-50	mA
VI	DC input voltage <sup>3</sup>		-0.5 to +7.0	V
Ι <sub>ΟΚ</sub>	DC output diode current	V <sub>O</sub> < 0	-50	mA
V <sub>OUT</sub>	DC output voltage <sup>3</sup>	Output in Off or High state	-0.5 to +7.0	V
		Output in Low state	128	mA
Ιουτ	DC output current	Output in High state	-64	
T <sub>stg</sub>	Storage temperature range		-65 to +150	°C

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150°C.

3. The input and output negative voltage ratings may be exceeded if the input and output clamp current ratings are observed.

#### **RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	2.5V RAN	2.5V RANGE LIMITS		3.3V RANGE LIMITS		
		MIN	MAX	MIN	MAX	UNIT	
V <sub>CC</sub>	DC supply voltage	2.3	2.7	3.0	3.6	V	
VI	Input voltage	0	5.5	0	5.5	V	
V <sub>IH</sub>	High-level input voltage	1.7		2.0		V	
V <sub>IL</sub>	Input voltage		0.7		0.8	V	
I <sub>ОН</sub>	High-level output current		-8		-32	mA	
	Low-level output current		8		32	mA	
IOL	Low-level output current; current duty cycle $\leq$ 50%; f $\geq$ 1kHz		24		64	ША	
Δt/Δv	Input transition rise or fall rate; Outputs enabled		10		10	ns/V	
T <sub>amb</sub>	Operating free-air temperature range	-40	+85	-40	+85	°C	

#### 74ALVT16543

					LIMITS		
SYMBOL	PARAMETER	TEST CONDITIONS		Temp = -40°C to +8		+85°C	υΝΙΤ
				MIN	TYP <sup>1</sup>	MAX	1
V <sub>IK</sub>	Input clamp voltage	V <sub>CC</sub> = 3.0V; I <sub>IK</sub> = -18mA			-0.85	-1.2	V
	LPate to a factor to a factor	$V_{CC} = 3.0$ to 3.6V; $I_{OH} = -100\mu A$		V <sub>CC</sub> -0.2	V <sub>CC</sub>		v
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = 3.0V; I <sub>OH</sub> = -32mA		2.0	2.3		l V
		V <sub>CC</sub> = 3.0V; I <sub>OL</sub> = 100µA			0.07	0.2	
		V <sub>CC</sub> = 3.0V; I <sub>OL</sub> = 16mA			0.25	0.4	1
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = 3.0V; I <sub>OL</sub> = 32mA			0.3	0.5	V
		$V_{CC} = 3.0V; I_{OL} = 64mA$			0.4	0.55	
V <sub>RST</sub>	Power-up output low voltage <sup>6</sup>	$V_{CC} = 3.6V$ ; $I_O = 1mA$ ; $V_I = V_{CC}$ or GND				0.55	V
		$V_{CC} = 3.6V; V_I = V_{CC} \text{ or GND}$	Control pins		0.1	±1	μA
	Input leakage current	$V_{CC} = 0 \text{ or } 3.6 \text{V}; \text{ V}_{I} = 5.5 \text{V}$			0.1	10	
łı	input leakage current	$V_{CC} = 3.6V; V_{I} = V_{CC}$	Data pins <sup>4</sup>		0.5	1	
		$V_{CC} = 3.6V; V_{I} = 0V$	Data pins .		0.1	-5	1
I <sub>OFF</sub>	Off current	$V_{CC} = 0V$ ; $V_{I}$ or $V_{O} = 0$ to 4.5V			0.1	±100	μA
	Due Hald summer	$V_{CC} = 3V; V_{I} = 0.8V$		75	130		
I <sub>HOLD</sub>	Bus Hold current	$V_{CC} = 3V; V_1 = 2.0V$		-75	-140		μA
	Data inputs <sup>7</sup>	$V_{CC} = 0V \text{ to } 3.6V; V_{CC} = 3.6V$		±500			1
I <sub>EX</sub>	Current into an output in the High state when $V_O > V_{CC}$	V <sub>O</sub> = 5.5V; V <sub>CC</sub> = 3.0V			50	125	μA
I <sub>PU/PD</sub>	Power up/down 3-State output current <sup>3</sup>	$V_{CC} \leq$ 1.2V; $V_O$ = 0.5V to $V_{CC};~V_I$ = GNE OE/OE = Don't care	$V_{CC} \le 1.2V$ ; $V_O = 0.5V$ to $V_{CC}$ ; $V_I = GND$ or $V_{CC}$ OE/OE = Don't care		40	±100	μA
I <sub>CCH</sub>		$V_{CC}$ = 3.6V; Outputs High, $V_I$ = GND or $V_{CC}$ , $I_O$ = 0			0.07	0.1	
I <sub>CCL</sub>	Quiescent supply current	$V_{CC}$ = 3.6V; Outputs Low, $V_{I}$ = GND or $V_{CC,\ I_{O}}$ = 0			3.6	5	mA
I <sub>CCZ</sub>	1	$V_{CC}$ = 3.6V; Outputs Disabled; $V_{I}$ = GNE	) or $V_{CC, I_{O}} = 0^5$		0.07	0.1	1
$\Delta I_{CC}$	Additional supply current per input pin <sup>2</sup>	$V_{CC} = 3V$ to 3.6V; One input at $V_{CC}$ -0.6 Other inputs at $V_{CC}$ or GND	V,		0.04	0.4	mA

#### DC ELECTRICAL CHARACTERISTICS (3.3V ± 0.3V RANGE)

NOTES:

All typical values are at V<sub>CC</sub> = 3.3V and T<sub>amb</sub> = 25°C.
This is the increase in supply current for each input at the specified voltage level other than V<sub>CC</sub> or GND
This parameter is valid for any V<sub>CC</sub> between 0V and 1.2V with a transition time of up to 10msec. From V<sub>CC</sub> = 1.2V to V<sub>CC</sub> = 3.3V ± 0.3V a transition time of 100µsec is permitted. This parameter is valid for T<sub>amb</sub> = 25°C only.
Unused pins at V<sub>CC</sub> or GND.

5. I<sub>CCZ</sub> is measured with outputs pulled up to V<sub>CC</sub> or pulled down to ground.
6. For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.

7. This is the bus hold overdrive current required to force the input to the opposite logic state.

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					LIMITS		
SYMBOL	PARAMETER	TEST CONDITIONS		Temp =	-40°C to	0°C to +85°C	
				MIN	TYP <sup>1</sup>	MAX	1
VIK	Input clamp voltage	V <sub>CC</sub> = 2.3V; I <sub>IK</sub> = -18mA			-0.85	-1.2	V
		$V_{CC} = 2.3$ to 3.6V; $I_{OH} = -100\mu A$		V <sub>CC</sub> -0.2	V <sub>CC</sub>		
V <sub>OH</sub>	High-level output voltage	V <sub>CC</sub> = 2.3V; I <sub>OH</sub> = -8mA		1.8	2.1		V
		V <sub>CC</sub> = 2.3V; I <sub>OL</sub> = 100μA			0.07	0.2	
V <sub>OL</sub>	Low-level output voltage	V <sub>CC</sub> = 2.3V; I <sub>OL</sub> = 24mA			0.3	0.5	V
		V <sub>CC</sub> = 2.3V; I <sub>OL</sub> = 8mA				0.4	1
V <sub>RST</sub>	Power-up output low voltage <sup>7</sup>	$V_{CC}$ = 2.7V; $I_{O}$ = 1mA; $V_{I}$ = $V_{CC}$ or GND				0.55	V
		$V_{CC} = 2.7V; V_I = V_{CC}$ or GND	Control pins		0.1	±1	
		$V_{CC} = 0 \text{ or } 2.7 \text{V}; \text{ V}_{\text{I}} = 5.5 \text{V}$			0.1	10	1
II.	II Input leakage current	$V_{CC} = 2.7V; V_I = 5.5V$			0.1	20	μA
		$V_{CC} = 2.7V; V_{I} = V_{CC}$	Data pins <sup>4</sup>		0.1	10	
		$V_{CC} = 2.7V; V_{I} = 0$			0.1	-5	1
I <sub>OFF</sub>	Off current	$V_{CC} = 0V; V_{I} \text{ or } V_{O} = 0 \text{ to } 4.5V$			0.1	±100	μΑ
I <sub>HOLD</sub>	Bus Hold current	$V_{CC} = 2.3V; V_{I} = 0.7V$			120		μA
	Data inputs <sup>6</sup>	V <sub>CC</sub> = 2.3V; V <sub>I</sub> = 1.7V			-6		μΑ
$I_{EX}$	Current into an output in the High state when $V_O > V_{CC}$	$V_{O} = 5.5V; V_{CC} = 2.3V$			50	125	μΑ
I <sub>PU/PD</sub>	Power up/down 3-State output current <sup>3</sup>	$V_{CC} \leq$ 1.2V; $V_{O}$ = 0.5V to $V_{CC};$ $V_{I}$ = GNE OE/OE = Don't care	or V <sub>CC</sub> ;		40	100	μA
I <sub>CCH</sub>		$V_{CC}$ = 2.7V; Outputs High, $V_I$ = GND or $V_{CC}$ , $I_O$ = 0			0.04	0.1	
I <sub>CCL</sub>	Quiescent supply current	$V_{CC}$ = 2.7V; Outputs Low, $V_{I}$ = GND or $V_{CC}$ , $I_{O}$ = 0			2.6	4.5	mA
I <sub>CCZ</sub>	1	$V_{CC}$ = 2.7V; Outputs Disabled; $V_{I}$ = GND	) or $V_{CC}$ , $I_{O} = 0^5$		0.04	0.1	1
$\Delta I_{CC}$	Additional supply current per input pin <sup>2</sup>	$V_{CC}$ = 2.3V to 2.7V; One input at $V_{CC}$ -0. Other inputs at $V_{CC}$ or GND	6V,		0.01	0.4	mA

#### DC ELECTRICAL CHARACTERISTICS (2.5V ±0.2V RANGE)

NOTES:

1. All typical values are at  $V_{CC} = 2.5V$  and  $T_{amb} = 25^{\circ}C$ . 2. This is the increase in supply current for each input at the specified voltage level other than  $V_{CC}$  or GND 3. This parameter is valid for any  $V_{CC}$  between 0V and 1.2V with a transition time of up to 10msec. From  $V_{CC} = 1.2V$  to  $V_{CC} = 2.5V \pm 0.2V$  a transition time of 100µsec is permitted. This parameter is valid for  $T_{amb} = 25^{\circ}C$  only.

4. Unused pins at  $V_{CC}$  or GND. 5.  $I_{CCZ}$  is measured with outputs pulled up to  $V_{CC}$  or pulled down to ground.

6. Not guaranteed.

7. For valid test results, data must not be loaded into the flip-flops (or latches) after applying power.

## 74ALVT16543

#### AC CHARACTERISTICS (3.3V $\pm$ 0.3V RANGE)

GND = 0V;  $t_R = t_F = 2.5$ ns;  $C_L = 50$ pF;  $R_L = 500\Omega$ ;  $T_{amb} = -40$ °C to +85°C.

SYMBOL	PARAMETER	WAVEFORM	V <sub>C</sub>	<sub>C</sub> = 3.3V ± 0.	.3V	UNIT
			MIN	TYP <sup>1</sup>	MAX	1
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nAx to nBx or nBx to nAx	2	0.5 0.5	1.6 1.8	2.5 3.0	ns
t <sub>PLH</sub>	Propagation delay	1	1.0	2.4	4.0	ns
t <sub>PHL</sub>	nLEBA to nAx, nLEAB to nBx	2	1.0	2.4	4.0	
t <sub>PZH</sub>	Output enable time	4	1.0	2.3	4.0	ns
t <sub>PZL</sub>	nOEBA to nAx, nOEAB to nBx	5	1.0	1.8	3.1	
t <sub>PHZ</sub>	Output disable time	4	1.0	3.1	4.7	ns
t <sub>PLZ</sub>	nOEBA to nAx, nOEAB to nBx	5	1.0	2.7	4.0	
t <sub>PZH</sub>	Output enable time	4	1.0	2.5	4.2	ns
t <sub>PZL</sub>	nEBA to nAx, nEAB to nBx	5	1.0	1.9	3.1	
t <sub>PHZ</sub>	Output disable time	4	1.0	2.9	4.5	ns
t <sub>PLZ</sub>	nEBA to nAx, nEAB to nBx	5	1.0	2.4	3.8	

NOTE:

1. All typical values are at V\_{CC} = 3.3V and T\_{amb} = 25°C.

## $\label{eq:action} \begin{array}{l} \textbf{AC SETUP REQUIREMENTS (3.3V \pm 0.3V RANGE)} \\ \textbf{GND} = 0V; \ t_R = t_F = 2.5 \text{ns}; \ C_L = 50 \text{pF}; \ R_L = 500 \Omega; \ T_{amb} = -40^\circ \text{C} \ \text{to} \ +85^\circ \text{C}. \end{array}$

		LIMITS		ITS	
SYMBOL	PARAMETER	WAVEFORM	V <sub>CC</sub> = 3.3	3V ±0.3V	UNIT
			MIN	ТҮР	
t <sub>s</sub> (H) t <sub>s</sub> (L)	Setup time nAx to nLEAB, nBx to nLEBA	3	0.0 0.7	-0.8 -0.3	ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time nAx to nLEAB, nBx to nLEBA	3	1.5 1.5	0.4 0.8	ns
t <sub>s</sub> (H) t <sub>s</sub> (L)	Setup time nAx to nEAB, nBx to nEBA	3	0.5 1.1	-0.8 -0.2	ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time nAx to nEAB, nBx to nEBA	3	1.2 2.0	0.3 1.1	ns
t <sub>W</sub> (L)	Latch enable pulse width, Low	3	1.5		ns

### 74ALVT16543

#### AC CHARACTERISTICS (2.5V ±0.2V RANGE)

GND = 0V;  $t_R = t_F = 2.5$ ns;  $C_L = 50$ pF;  $R_L = 500\Omega$ ;  $T_{amb} = -40$ °C to +85°C.

SYMBOL	PARAMETER	WAVEFORM	V <sub>C</sub>	$c = 2.5V \pm 0.00$	.2V	UNIT
			MIN	TYP <sup>1</sup>	MAX	1
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay nAx to nBx or nBx to nAx	2	1.0 1.0	1.8 2.7	5.1 4.5	ns
t <sub>PLH</sub>	Propagation delay	1	1.5	3.9	6.4	ns
t <sub>PHL</sub>	nLEBA to nAx, nLEAB to nBx	2	1.5	3.6	5.9	
t <sub>PZH</sub>	Output enable time	4	1.5	4.0	6.5	ns
t <sub>PZL</sub>	nOEBA to nAx, nOEAB to nBx	5	1.5	2.7	4.6	
t <sub>PHZ</sub>	Output disable time	4	1.5	3.7	5.6	ns
t <sub>PLZ</sub>	nOEBA to nAx, nOEAB to nBx	5	1.5	2.6	4.0	
t <sub>PZH</sub>	Output enable time	4	1.5	4.2	7.0	ns
t <sub>PZL</sub>	nEBA to nAx, nEAB to nBx	5	1.5	2.8	5.0	
t <sub>PHZ</sub>	Output disable time	4	1.5	3.6	5.6	ns
t <sub>PLZ</sub>	nEBA to nAx, nEAB to nBx	5	1.5	2.4	3.9	

NOTE:

1. All typical values are at V<sub>CC</sub> = 2.5V and T<sub>amb</sub> = 25°C.

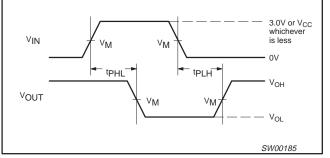
#### AC SETUP REQUIREMENTS (2.5V $\pm$ 0.2V RANGE)

GND = 0V;  $t_R = t_F = 2.5ns$ ;  $C_L = 50pF$ ;  $R_L = 500\Omega$ ;  $T_{amb} = -40^{\circ}C$  to +85°C.

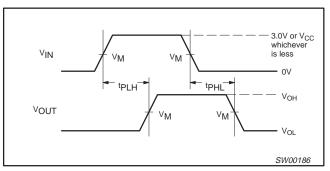
			LIM		
SYMBOL	PARAMETER	WAVEFORM	V <sub>CC</sub> = 2.5	5V ±0.2V	UNIT
			MIN	TYP	
t <sub>s</sub> (H) t <sub>s</sub> (L)	Setup time nAx to nLEAB, nBx to nLEBA	3	0 1.0	-0.9 0.2	ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time nAx to nLEAB, nBx to nLEBA	3	0.8 1.7	-0.2 1.0	ns
t <sub>s</sub> (H) t <sub>s</sub> (L)	Setup time nAx to nEAB, nBx to nEBA	3	0 1.5	-1.0 0.4	ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time nAx to nEAB, nBx to nEBA	3	0.5 2.0	-0.2 1.3	ns
t <sub>W</sub> (L)	Latch enable pulse width, Low	3	1.5		ns

#### AC WAVEFORMS

For all waveforms  $V_{M}$  = 1.5V or  $V_{CC}$  / 2, whichever is less.

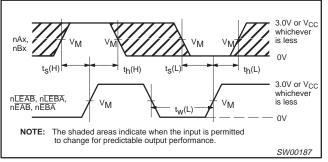




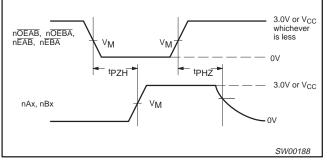


Waveform 2. Propagation Delay For Non-Inverting Output

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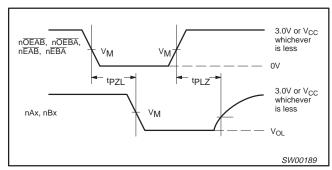


Waveform 3. Data Setup and Hold Times and Latch Enable **Pulse Width** 

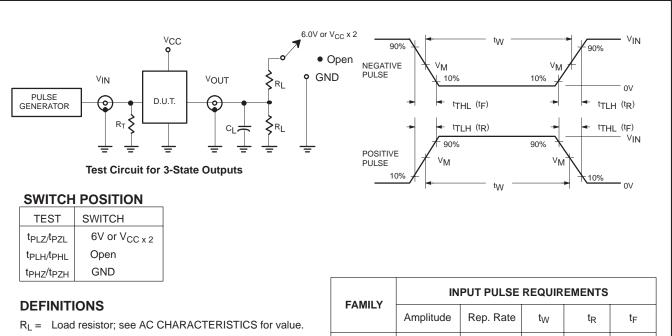


Waveform 4. 3-State Output Enable Time to High Level and Output Disable Time from High Level

#### **TEST CIRCUIT AND WAVEFORMS**



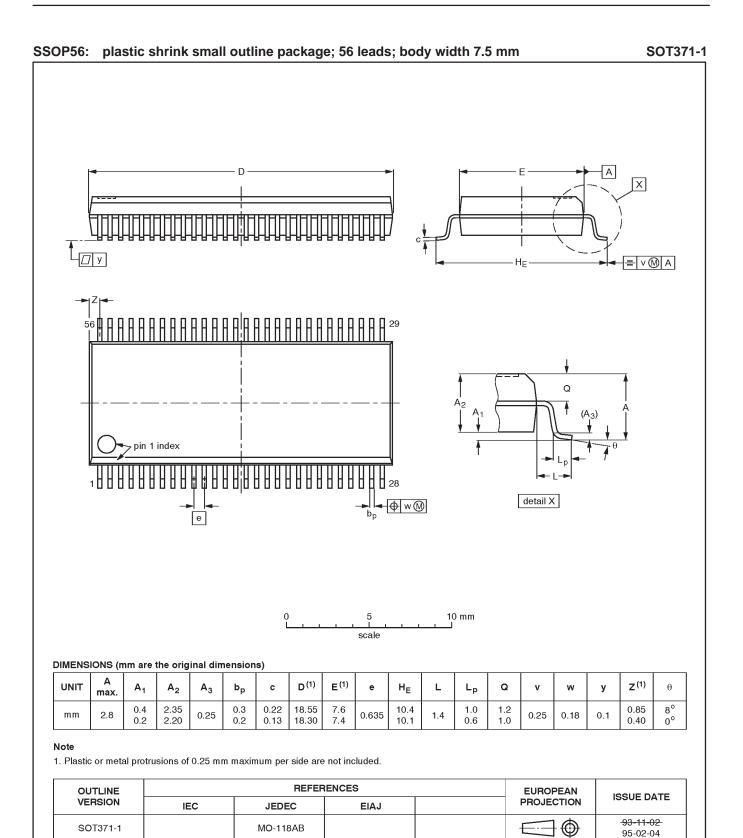
Waveform 5. 3-State Output Enable Time to Low Level and **Output Disable Time from Low Level** 



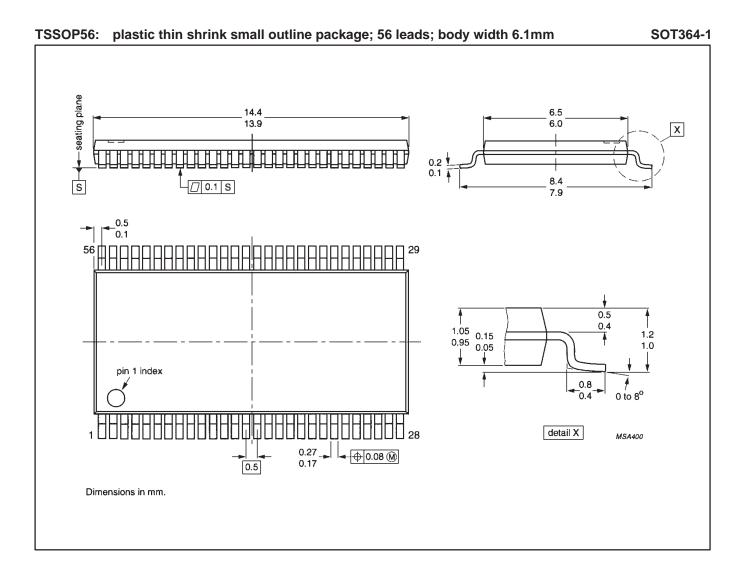
- C<sub>L</sub> = Load capacitance includes jig and probe capacitance: See AC CHARACTERISTICS for value.
- $R_T$  = Termination resistance should be equal to  $Z_{OUT}$  of pulse generators.

FAMILY	INPUT PULSE REQUIREMENTS						
FAMILI	Amplitude	Rep. Rate	t <sub>W</sub>	t <sub>R</sub>	t <sub>F</sub>		
74ALVT16	3.0V or V <sub>CC</sub> whichever is less	≤10MHz	500ns	≤2.5ns	≤2.5ns		

## 74ALVT16543



## 74ALVT16543



## 74ALVT16543

NOTES

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#### Data sheet status

Data sheet status	Product status	Definition <sup>[1]</sup>
Objective specification	Development	This data sheet contains the design target or goal specifications for product development. Specification may change in any manner without notice.
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[1] Please consult the most recently issued datasheet before initiating or completing a design.

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